Abstracts

A Novel MMIC Source Impedance Tuner for On-Wafer Microwave Noise Parameter Measurements

C.E. Collins, R.D. Pollard and R.E. Miles. "A Novel MMIC Source Impedance Tuner for On-Wafer Microwave Noise Parameter Measurements." 1996 Microwave and Millimeter-Wave Monolithic Circuits Symposium Digest 98. (1996 [MCS]): 123-126.

A novel MMIC source impedance tuner is reported which can be incorporated into a wafer probe tip. This eliminates the effect of cable and probe losses on reflection coefficient, which enables higher magnitudes to be synthesized at the test device input than for conventional tuners, potentially increasing noise parameter measurement accuracy.

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